

## **Maximum Ratings** ( $@T_A = +25^{\circ}C$ , unless otherwise specified.)

Characteristic			Symbol	Value	Unit
Drain-Source Voltage			V <sub>DSS</sub>	20	V
Gate-Source Voltage			V <sub>GSS</sub>	±12	V
Continuous Drain Current (Note 6) V <sub>GS</sub> = 4.5V	Steady State	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I <sub>D</sub>	0.9 0.7	А
Pulsed Drain Current (10µs Pulse, Duty Cycle = 1%)			I <sub>DM</sub>	3.0	Α
Maximum Body Diode Forward Current (Note 6)			Is	0.8	Α

# Thermal Characteristics (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic		Symbol	Value	Unit
Total Power Dissipation (Note 5)		$P_{D}$	0.45	W
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	$R_{ heta JA}$	280	°C/W
Total Power Dissipation (Note 6)		P <sub>D</sub>	0.89	W
Thermal Resistance, Junction to Ambient (Note 6)	Steady State	$R_{ heta JA}$	140	°C/W
Thermal Resistance, Junction to Case (Note 6)		R <sub>θ</sub> JC	112	°C/W
Operating and Storage Temperature Range		T <sub>J,</sub> T <sub>STG</sub>	-55 to +150	°C

# **Electrical Characteristics** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

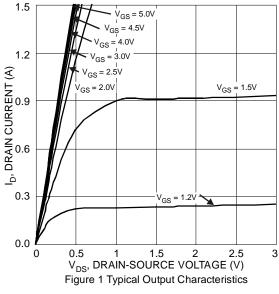
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 7)							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	20	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$	
Zero Gate Voltage Drain Current T <sub>J</sub> = +25°C	I <sub>DSS</sub>	_	_	100	nA	$V_{DS} = 20V, V_{GS} = 0V$	
Gate-Source Leakage	I <sub>GSS</sub>	_	_	±1.0	μΑ	$V_{GS} = \pm 4.5V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 7)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	0.45	_	1.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
		_	0.35	0.6	Ω	$V_{GS} = 4.5V, I_D = 200mA$	
Static Drain-Source On-Resistance	<sub> </sub>	_	0.45	0.8		$V_{GS} = 2.5V, I_D = 200mA$	
Static Drain-Source On-Resistance	R <sub>DS(ON)</sub>	_	0.6	1.0		$V_{GS} = 1.8V, I_D = 100mA$	
		_	0.7	1.6		$V_{GS} = 1.5V, I_D = 50mA$	
Diode Forward Voltage	$V_{SD}$	_	0.7	1.2	V	$V_{GS} = 0V, I_{S} = 500mA$	
DYNAMIC CHARACTERISTICS (Note 8)		•	•	•	•		
Input Capacitance	C <sub>iss</sub>	_	52	_	pF	V <sub>DS</sub> = 16V, V <sub>GS</sub> = 0V, f = 1.0MHz	
Output Capacitance	Coss	_	4.8	_	pF		
Reverse Transfer Capacitance	C <sub>rss</sub>	_	3.1	_	pF		
Gate Resistance	Rg	_	95	_	Ω	$V_{DS} = 0V$ , $V_{GS} = 0V$	
Total Gate Charge	Qq	_	0.7	_	nC	451/1/ 401/	
Gate-Source Charge	Q <sub>gs</sub>	_	0.09	_	nC	$V_{GS} = 4.5V, V_{DS} = 10V,$ $I_{D} = 250 \text{mA}$	
Gate-Drain Charge	Q <sub>qd</sub>	_	0.05	_	nC		
Turn-On Delay Time	t <sub>D(ON)</sub>	_	3.7	_	ns	$\begin{aligned} & V_{DD} = 10 V,  V_{GS} = 4.5 V, \\ & R_L = 47 \Omega,  R_G = 10 \Omega, \\ & I_D = 200 \text{mA} \end{aligned}$	
Turn-On Rise Time	t <sub>R</sub>	_	2.4	_	ns		
Turn-Off Delay Time	t <sub>D(OFF)</sub>	_	20.9	_	ns		
Turn-Off Fall Time	t <sub>F</sub>	_	5.6	_	ns		

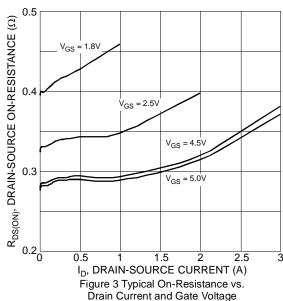
Notes:

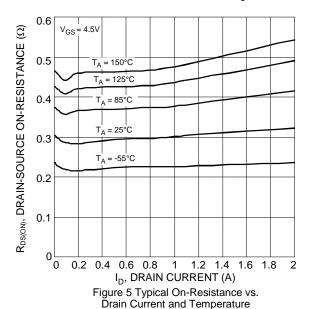
- 5. Device mounted on FR-4 PC board, with minimum recommended pad layout, single sided.
- Device mounted on FR-4 substrate PC board, 2oz copper, with thermal vias to bottom layer 1-inch square copper plate.
  Short duration pulse test used to minimize self-heating effect.
  Guaranteed by design. Not subject to production testing.

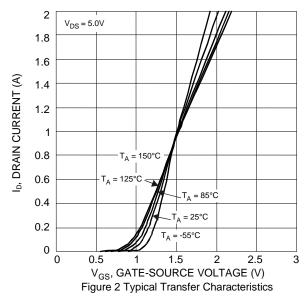


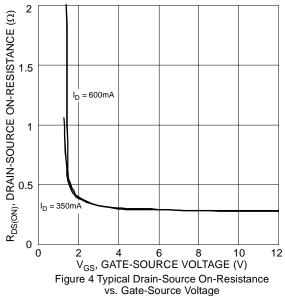












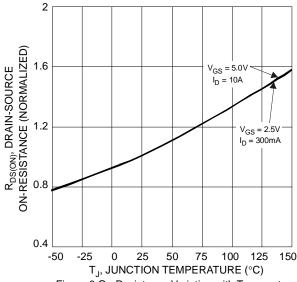
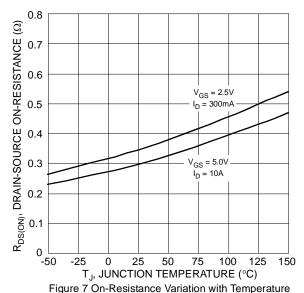
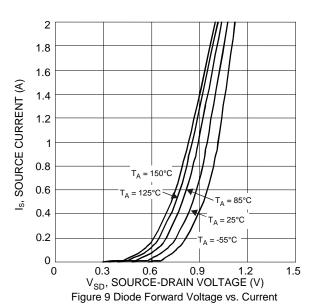
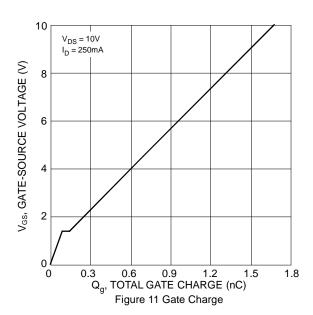


Figure 6 On-Resistance Variation with Temperature

### DMN2450UFD







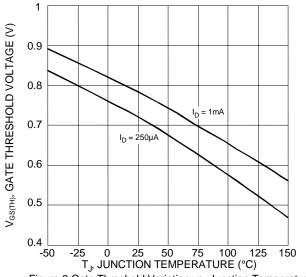
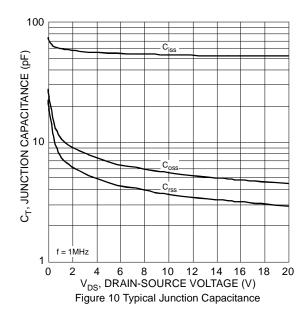
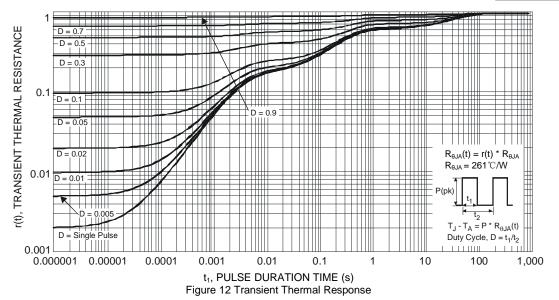


Figure 8 Gate Threshold Variation vs. Junction Temperature



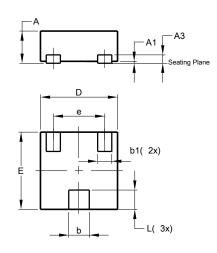




### **Package Outline Dimensions**

Please see http://www.diodes.com/package-outlines.html for the latest version.

#### X1-DFN1212-3

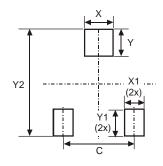


X1-DFN1212-3					
Dim	Min	Max	Тур		
Α	0.47	0.53	0.50		
A1	0	0.05	0.02		
A3	-	-	0.13		
b	0.27	0.37	0.32		
b1	0.17	0.27	0.22		
D	1.15	1.25	1.20		
Е	1.15	1.25	1.20		
е	-	-	0.80		
L	0.25	0.35	0.30		
All Dimensions in mm					

## **Suggested Pad Layout**

Please see http://www.diodes.com/package-outlines.html for the latest version.

#### X1-DFN1212-3



Dimensions	Value (in mm)
С	0.80
Х	0.42
X1	0.32
Υ	0.50
Y1	0.50
Y2	1.50



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